Notification about Substitutes for UQFN10 Products to be Discontinued (Urgent request)

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State of production of UQFN10 products

Products of package UQFN10 are currently manufactured at two sites. Overseas subcontractor Company Y, however, has unilaterally informed us that it will discontinue the package products. In addition, domestic subcontractor Company Z has informed us that a frame manufacturer will stop producing the frames for UQFN10B products.

For continued production, we are preparing substitute products for those products to be discontinued as follows. We would appreciate it if you would promptly look into whether you can accept them.

Production site	Package	No.	Product name	State of production	Request to our customers	
Overseas subcontractor:		#1	TC7USB40MU,LF(S	- The subcontractor has unilaterally informed that it will discontinue these products.	It is difficult to continue supplying these products. Please change to the substitute products #3.	
Company Y %1	UQINIU	πΙ	TC7USB42MU,LF(S	the products will be discontinued and asking our customers to inform us of necessary quantity of these products.		
		#0	TC7USB40MU,LF(S2	The frame manufacturer has informed that it will discontinue the frames for	These products, which will be discontinued, are limited in supply.	
Domestic subcontractor:	UQFN10B	#2	TC7USB42MU,LF(S2	these products.	Please change to the substitute products #3.	
Company Z			TC7USB40MU,LF(S2E	We are preparing to start mass-	Please approve these products.	
		#3	TC7USB42MU,LF(S2E	frames in September 2021.		

X1 Our person in charge of foundry business is discussing the issue of discontinued production with the overseas subcontractor. However, no major progress has been made so far. We apologize for the short notice, but we would like to supply substitutes and ask for your approval.

The following pages show the details of the changes.

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1. Schedule for supplying products

Products with #3 are scheduled to be mass-produced from Oct 2021.

The domestic subcontractor has produced similar packages including DFN5B for around 10 years.

Т

Please contact our sales representatives to ask for samples of the substitutes (products # 3). Your cooperation would be appreciated.

Item		2021										2022			
		Apr.	May	Jun.	J <mark>ul</mark> .	Aug.	Sep.	Oct.	Nov.	Dec.	Jan.	Apr.	Jul.	Oct.	Jan.
#1	TC7USB40MU,LF(S			Out of											
#1	TC7USB42MU,LF(S			produc	tion										
#2	TC7USB40MU,LF(S2	In pr	oductic	on → (i Gather	inform	ation a	bout q	uantity	Pro	ducts w	ith old			
#2	TC7USB42MU,LF(S2	SB42MU,LF(S2						ners need production							
#2	TC7USB40MU,LF(S2E			Sta	i rt up pr	oductio					al ti	C to			
#3	TC7USB42MU,LF(S2E			Ja						pro					

2. Summary of changes

We have basically adopted the subcontractor's standard designs for materials, etc. The chips, which are supplied from a Japan factory, are not to change.

	Iten	n	Overseas subcontractor	Domestic s	ubcontractor					
	Package	name	UQFN10	UQ	FN10B					
	Numł	ber	# 1	#2	# 3					
Pro	oduct name	(Change in	TC7USB40MU,LF(S	TC7USB40MU,LF(S <mark>2</mark>	TC7USB40MU,LF(S2E					
ac	ditional coo	de "ADDC")	TC7USB42MU,LF(S	TC7USB42MU,LF(S <mark>2</mark>	TC7USB42MU,LF(S <mark>2E</mark>					
Drew			Only the drawings change. No change in product size and characteristics.							
Draw		echnical data)	Land pattern: Large	Land pa	ttern: Small					
luct appearance	Appearanc	e	The photos above are TC7SB40MU.	Image: A constraint of the second sec	are TC7SB40MU.					
rod			The electrodes are exposed on the sides.							
	Mark		No change in pro	Bauct ID code: IC7SB40MU = A	IC/SB42IMU = B					
		Trace code	Year code, week code Year code, week code, internal control number							
	QCS		Subcontractor's standard QCS Subcontractor's standard QCS							
bu	Chip		No change: Supplied from Japan (Japan Semiconductor Corporation)							
facturi	Frame stru	cture (plating)	Cu alloy (Ni/Pd/Au)	Ni electroforming (Ag/Pd/Ni/Au)	Ni electroforming (Ag/Ni/Au)					
anu	Product' ba	ack side		Au						
Σ	Bonding		Au	P	d-Cu					
	Resin			No change: Halogen-free						
	Labelling		Assembled in Thailand	Assembl	ed in Japan					
bu	Device qua	ntity per reel		No change: 3000 pcs/reel						
acki	Reel		Blue: Subcontractor's standard reel	Black: Subcontra	ctor's standard reel					
<u>ь</u>	Inner carto	n	Subcontractor's standard carton 1 reel/carton	Subcontractor's standard carton Max 10 reels/carton						

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3. Change points (Summary of this document)

	ltem		Content	Item number
Package name				
Number			Summary of changes	2
Product name (Cha	nge in additior	nal code "ADDC")		
	······································		Comparison in drawing	4.4-1
Drawing in TD (Tech	nnical data)		Land pattern	4.4-2
	Appearance		Comparison in appearance	4.4-3
Product	Marile	ID code		
appearance	IVIAIK	Trace code	Explanation about marking	4.4-4
	QCS	•	Comparison in QCS	4.4-5
	Chip		-	-
Manage for a transition of	Frame structu	re (Plating)		
Manufacturing	External part		Comparison in structural drawing	
	Bonding		(#1 vs #3)	4.4-6
	Resin			
	Labelling		Descriptions on label	4.4-7
Decking	Tape dimension	ons		
Packing	Reel		Descriptions in packing specifications	4.4-8 4.4-9
	Inner carton			т.т <i>у</i>
	Electrical char	acteristics	Comparison in initial characteristics	5
Product function	Reliability		Reliability data (#3)	6
	Mounting eva	luation	Mounting evaluation	7
Finished product	Evaluation on	finished product	Comparison in external dimensions	8

4. Change point: Technical data (TD)-External drawing

4-1) There are changes mainly in shape of the product's back.



4. Change point: Technical data (TD)- Land pattern

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4-2) The following shows a difference in land pattern.



Recommended land size for mounting:

We have confirmed that the land size of the overseas subcontractor's products can be used to mount the substitute products. However, we recommend that your company apply the land size according to the change in terminal dimensions when fabricating a new board.

4. Change point: Comparison in product appearance

4-3) Photos of six sides

Representative product: TC7USB40MU

	Front	Back	Left side	Right side	Top side	Bottom side
Product before change #1 (Overseas subcontractor)	ъ 1. О		日始第一			M. M. M
Product after change #2 (Domestic subcontractor)	0151 A 151					
Product after change #3 (Domestic subcontractor)	• 151 A 01					



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4. Change point: Mark (ID code, trace code)

4-4) Explanation about marking is shown below.



X Please see Appendix (ID code, trace code) for the details of Lot Code and Internal Control Code.

4. Change point: QCS

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4-5) Control plan (QC process flow)

Product	before change (Overseas subco	ontractor)		Produc	t after change (D	omestic subco	ontractor)
Manufact Flow Chart	ture Production Process	Items Controlled/Inspected	Check Frequency		Manu Flow Chart	facturing Process Process	Items Controlled/Inspected	Check Frequency
	(Chip) (Frame) Die Bonding Appearance Inspection	Temperature Bonding Status	Once / Week Once / Lot Change			(Wafer) Backgrinding (Die mount material (DAF)) Dicing (Substrate + Electrode)	Wafer thickness	Once/Day
×	Curing (Bonding Wire) Wire Bonding	Bonding Strength	Once / Shift			(Epoxy resin) Die bonding (Bonding wire) Wire bonding	Appearance Bonding strength	Once/Lot Once/Week
2	Appearance Inspection	Bonding Status	Once / Shift		Þ	Appearance inspection	Bonding condition	Once/Lot
	(Molding Resin) Molding Marking	Temperature	Once / Day			(Molding resin) Molding	Temperature	Once/Day
	Appearance Inspection Sheet Sticking	Marking Status	Once / Lot			Substrate removing Marking Sheet attaching Dicing	Appearance Appearance	Once/Lot Once/Lot
	Appearance Inspection	Dicing Status	Once / Lot			Testing Appearance inspection	Electrical characteristics	
	Testing (Taping Material) Taping (Packing Material) Packing	Electrical Characteristics			V V	(Taping material) Taping (Packing material) Packing		
t t	Quality Monitoring Shipping	Electrical Characteristics Reliability test				Quality monitoring Shipping	Electrical characteristics Reliability testing	
Symbol	✓·Storage O:Open □ △:Special check O-□ · C	ation D:100%Test	☑: Sampling inspection		Symbol		ation □:100%Test □ heck	: Sampling inspection
The above process may be	changed or rationalized based o	n the result in our process.		The	above flow is subje	ct to change or streamlining based	on the track record of our pro	cess.

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4. Change point: Structural drawing

4-6) The structural drawings are shown below.

TC7USB40MU / TC7USB42MU



4. Change point: Labelling

4-7) Descriptions on the label are shown below.



4. Change point: Packing specifications

4-8) Change in tape dimensions



There is no change in tape pitch between the overseas and domestic products. (Adoption of each outsourced standard product)

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4. Change point: Packing specifications

4-8) Change in reel dimensions



There is no change in reel dimensions (180ϕ) between the overseas and domestic products. (Adoption of each outsourced standard product)

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4. Change point: Packing specifications

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4-9) Change in inner carton dimensions



(Adoption of each outsourced standard product)

5. Product function check

Comparison in initial characteristics

Initial characteristics (electrical characteristics) were measured. The measurements fell within the specifications. No differences were found in the results and no problems were found.

Representative product: TC7USB42MU

n=1Lot Ta=25°C

ltere	Cumple of	Measurement	S	pecifica	tion (TI	D)	#	1	#	2	#3		
item	Symbol	condition	Min	Тур	Max	Unit	Average	Average Cpk		Cpk	Average	Cpk	
Quiescent supply current	ICC	VIN=VCC or GND, IOUT=0A	-	-	1	uA	0.009	557	0.009	587	0.009	543	
ON-resistance	RON	VIS=0V, IIS=30mA	-	4.5	6	Ω	4.42	15.7	4.43	15.5	4.42	16.1	



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6. Reliability data

The following shows data on evaluations for the change.

Evaluation	ltem	Conditions	Result (Sample size = n)	Judg- ment	Data attached
Product	Solderability test	240°C/3s	10p	ОК	-
function check	Static load test	20N, 40N, 50N	12p	ОК	-
	Temperature cycle test (Pretreatment = Moisture absorption + Reflow)	-65°C(30 min) to 150°C(30 min), 100 cyc	30p	ОК	-
Reliability check	Pressure cooker test (Pretreatment = Moisture absorption + Reflow)	127°C/100% 96h	30p	ОК	-
	Salt atmosphere test (Use of results of evaluating antecedently developed package, DFN5B)	35°C/5% NaCl/48h	11p	ОК	-
	Mounting shear strength	Directions X, Y (Initial)	11p	ОК	Attached
wounting check	Shear test after mounting temperature cycle test	Directions X, Y (100 cyc)	11p	ОК	Attached

Confidential 7. Device mounting check (Mounting shear strength, mounting temperature cycle test)

Mounting shear strength and mounting temperature cycle tests were conducted. The results showed that both before and after the temperature cycle test, the shear strength of products after the change (#2, #3) was equivalent to that of products before the change (#1). No problems were found.



Reflow zone

Preheat

230°C or more / 30 - 50 sec 180 - 190°C / 60 - 120 sec

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8. Finished product check

Comparison in external dimensions

Product dimensions were measured. The measurements fell within the specifications. No differences were found in the results and no problems were found.

Representative product: TC7USB42MU

(n=10p×3 lots)

Num	ltom	А	В	С	D	E	F	G	Н	I	J	K
ber	nem	(mm)	(mm)	(mm)	(mm)	(mm)	(mm)	(mm)	(mm)	(mm)	(mm)	(mm)
	Avg	1.385	1.795	0.526	0.205	0.417	0.494	0.961	0.593	0.484	0.395	0.394
#1	Ср	5.92	6.53	11.87	5.56	4.98	7.83					
	Cpk	4.09	5.85	5.60	5.01	3.33	6.96					
Spec	: for #1	1.35~1.45	1.75~1.85	0.45~0.55	0.15~0.25	0.35~0.45	0.45~0.55	1.0typ	0.6typ	0.5typ	0.4typ	0.4typ
Jud	gment	ОК	ОК	ОК	ОК	ОК	OK	ОК	OK	ОК	ОК	ОК
				-								

Num	Itom	A	В	C	D	E	F	G	Н	J	K
ber	item	(mm)	(mm)	(mm)	(mm)	(mm)	(mm)	(mm)	(mm)	(mm)	(mm)
	Avg	1.394	1.795	0.476	0.215	0.326	0.489	0.998	0.297	0.396	0.395
#2	Ср	6.62	4.94	2.19	6.91	8.40	3.75	3.87	5.54		-
	Cpk	5.86	4.45	2.12	4.81	8.18	2.69	3.73	5.22		-
	Avg	1.394	1.802	0.485	0.205	0.320	0.469	1.000	0.296	0.400	0.405
#3	Ср	5.43	5.73	2.72	5.40	4.97	4.71	4.95	5.22		-
	Cpk	4.82	5.48	1.69	4.89	4.46	4.17	4.91	4.80		-
Spec ⁻	for #2, 3	1.35~1.45	1.75~1.85	0.45~0.5	0.15~0.25	0.275~0.375	0.425~0.525	0.95~1.05	0.25~0.35	0.4typ	0.4typ
Judgment		OK	OK	OK	OK	OK	OK	OK	OK	OK	OK









* Specification with upper and lower limits: Cpk, Cp, Average * Typ. value: Average

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Our Semiconductor and Storage products will always be a driving force to change the world

Toshiba Electronic Devices and Storage, together with our customers, will accelerate our future journey. We aim to be a company that will be chosen for our pioneering technology and spirit embedded in our products.

「Do the right thing/誠実であり続ける」

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Appendix

For reference: Specifications (ID code, trace code)

Lot traceability in the specifications is as follows.

Proc	Product before change (Overseas subcontractor)										ubcontractor)	Product after change (Domestic subcontractor)				
UQFN1	UQFN10											UQFN10B				
Marking												1	. Lot No. De	esignatio	n	
	Index Mark								tar k				Lot No. is (designated	l by year and month of manufacture as a combination of numbers and alphabet.	
Exp lanat i	Explanation for Lot code Product name Explanation for Lot code Processed week code Processed year code $\frac{1}{2}$ Processed year code Processed year code $\frac{1}{2}$ Processed year code Processed year code Proc							ode ot nam 2014 4	2015	2016 2017 2018 ···· 6 7 8 ····	10pin 9pin 8pin 1pin (1) (2) (3) (4) (5) (6) 7pin 3pin 4pin 5pin 3pin 4pin 5pin					
Processed	i week	code										Γ	Item	Mark Position	Contents	
Week	1	2	3	4	5	6	7	8	9	10			Year code	(1)	Year of manufacture: Last digit of Christian year.	
mark	1	2	3	4	5	6	7	8	9	0			Weekly code	(2)(3)	Week of manufacture: 1st week to 53rd week are denoted by 2 digit numbers	
Week mark	11	12 B	13	14 D	15 E	16 F	17 G	18 Н	19 .J	20 K			Product	(4)	A-TC7USB40MU_B-TC7USB42MU	
Week	21	22	23	24	25	26	27	28	29	30			abbreviation Internal	(
mark	L	м	N	Р	Q	R	т	υ	V	w			management	(5)(6)	Denoted by letters A to Z or 0 to 9 respectively.	
Week	31	32	33	34	35	36	37	38	39	40			code.			
mark	×	Y	z	а	c	d	f	h	į	i						
Week	41	42	43	44	45	46	47	48	49	50						
mark	ĸ	m	n	0	r	s	t	u	٧	w						
Week	51	52	53													
mark	×	У	z													